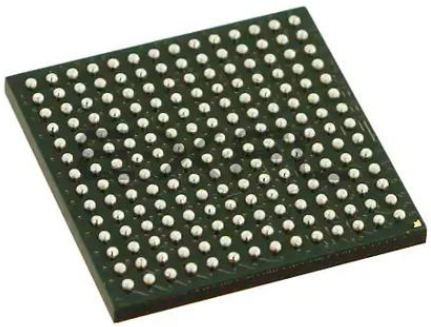

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Applications of "Embedded - Microcontrollers"

Details	
Product Status	Not For New Designs
Core Processor	Coldfire V2
Core Size	32-Bit Single-Core
Speed	150MHz
Connectivity	EBI/EMI, Ethernet, I²C, SPI, UART/USART
Peripherals	DMA, WDT
Number of I/O	97
Program Memory Size	-
Program Memory Type	ROMless
EEPROM Size	-
RAM Size	64K x 8
Voltage - Supply (Vcc/Vdd)	1.4V ~ 3.6V
Data Converters	-
Oscillator Type	External
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	196-LBGA
Supplier Device Package	196-LBGA (15x15)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mcf5271cvm150

1 MCF5271 Family Configurations

Table 1. MCF5271 Family Configurations

Module	MCF5270	MCF5271
ColdFire V2 Core with EMAC and Hardware Divide	x	x
System Clock	150 MHz	
Performance (Dhrystone/2.1 MIPS)	144	
Instruction/Data Cache	8 Kbytes	
Static RAM (SRAM)	64 Kbytes	
Interrupt Controllers (INTC)	2	2
Edge Port Module (EPORT)	x	x
External Interface Module (EIM)	x	x
4-channel Direct-Memory Access (DMA)	x	x
SDRAM Controller	x	x
Fast Ethernet Controller (FEC)	x	x
Hardware Encryption	—	x
Watchdog Timer (WDT)	x	x
Four Periodic Interrupt Timers (PIT)	x	x
32-bit DMA Timers	4	4
QSPI	x	x
UART(s)	3	3
I^2C	x	x
General Purpose I/O Module (GPIO)	x	x
JTAG - IEEE 1149.1 Test Access Port	x	x
Package	160 QFP, 196 MAPBGA	160 QFP, 196 MAPBGA

2 Block Diagram

The superset device in the MCF5271 family comes in a 196 mold array plastic ball grid array (MAPBGA) package. Figure 1 shows a top-level block diagram of the MCF5271.

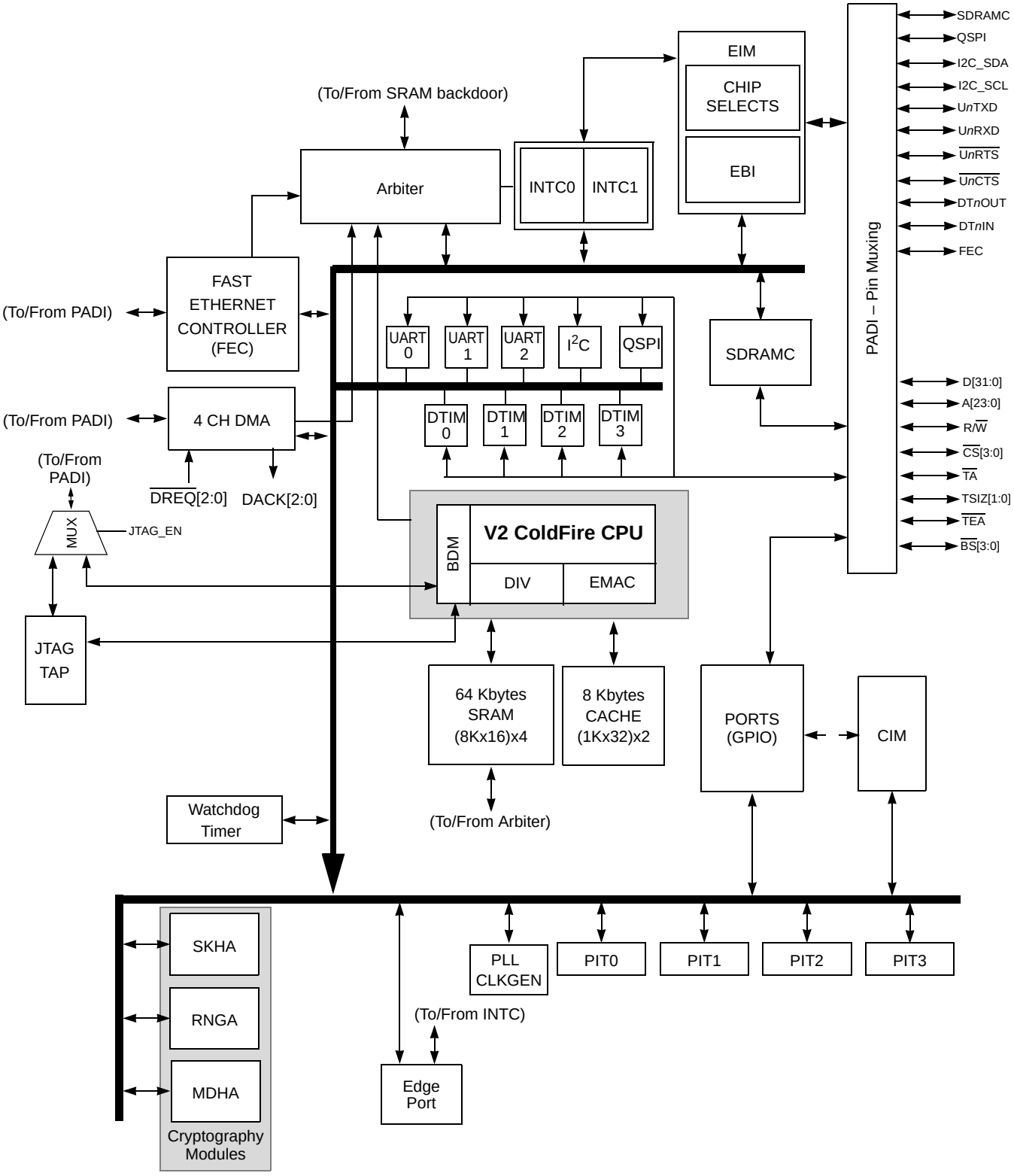


Figure 1. MCF5271 Block Diagram

3 Features

For a detailed feature list see the MCF5271 Reference Manual (MCF5271RM).

4 Signal Descriptions

This section describes signals that connect off chip, including a table of signal properties. For a more detailed discussion of the MCF5271 signals, consult the *MCF5271 Reference Manual* (MCF5271RM).

4.1 Signal Properties

Table 4 lists all of the signals grouped by function. The "Dir" column is the direction for the primary function of the pin. Refer to Section 6, "Mechanicals/Pinouts and Part Numbers," for package diagrams.

NOTE

In this table and throughout this document a single signal within a group is designated without square brackets (i.e., A24), while designations for multiple signals within a group use brackets (i.e., A[23:21]) and is meant to include all signals within the two bracketed numbers when these numbers are separated by a colon.

NOTE

The primary functionality of a pin is not necessarily its default functionality. Pins that are muxed with GPIO will default to their GPIO functionality.

Table 2. MCF5270 and MCF5271 Signal Information and Muxing

Signal Name	GPIO	Alternate 1	Alternate 2	Dir.[1]	MCF5270 MCF5271 160 QFP	MCF5270 MCF5271 196 MAPBGA
Reset						
$\overline{\text{RESET}}$	—	—	—	I	83	N13
$\overline{\text{RSTOUT}}$	—	—	—	O	82	P13
Clock						
EXTAL	—	—	—	I	86	M14
XTAL	—	—	—	O	85	N14
CLKOUT	—	—	—	O	89	K14
Mode Selection						
CLKMOD[1:0]	—	—	—	I	20,21	G5,H5
$\overline{\text{RCON}}$	—	—	—	I	79	K10
External Memory Interface and Ports						
A[23:21]	PADDR[7:5]	$\overline{\text{CS}}$[6:4]	—	O	126, 125, 124	B11, C11, D11

Table 3. Synchronous DRAM Signal Connections

Signal	Description
$\overline{\text{SD\_SRAS}}$	Synchronous row address strobe. Indicates a valid SDRAM row address is present and can be latched by the SDRAM. $\overline{\text{SD\_SRAS}}$ should be connected to the corresponding SDRAM $\overline{\text{SD\_SRAS}}$. Do not confuse $\overline{\text{SD\_SRAS}}$ with the DRAM controller's $\overline{\text{SD\_CS}}$[1:0], which should not be interfaced to the SDRAM $\overline{\text{SD\_SRAS}}$ signals.
$\overline{\text{SD\_SCAS}}$	Synchronous column address strobe. Indicates a valid column address is present and can be latched by the SDRAM. $\overline{\text{SD\_SCAS}}$ should be connected to the corresponding signal labeled $\overline{\text{SD\_SCAS}}$ on the SDRAM.
$\overline{\text{DRAMW}}$	DRAM read/write. Asserted for write operations and negated for read operations.
$\overline{\text{SD\_CS}}$[1:0]	Row address strobe. Select each memory block of SDRAMs connected to the MCF5271. One $\overline{\text{SD\_CS}}$ signal selects one SDRAM block and connects to the corresponding $\overline{\text{CS}}$ signals.
SD_CKE	Synchronous DRAM clock enable. Connected directly to the CKE (clock enable) signal of SDRAMs. Enables and disables the clock internal to SDRAM. When CKE is low, memory can enter a power-down mode where operations are suspended or they can enter self-refresh mode. SD_CKE functionality is controlled by DCR[COC]. For designs using external multiplexing, setting COC allows SD_CKE to provide command-bit functionality.
$\overline{\text{BS}}$[3:0]	Column address strobe. For synchronous operation, $\overline{\text{BS}}$[3:0] function as byte enables to the SDRAMs. They connect to the DQM signals (or mask qualifiers) of the SDRAMs.
CLKOUT	Bus clock output. Connects to the CLK input of SDRAMs.

5.7.1.2 Address Multiplexing

See the SDRAM controller module chapter in the *MCF5271 Reference Manual* for details on address multiplexing.

5.7.2 Ethernet PHY Transceiver Connection

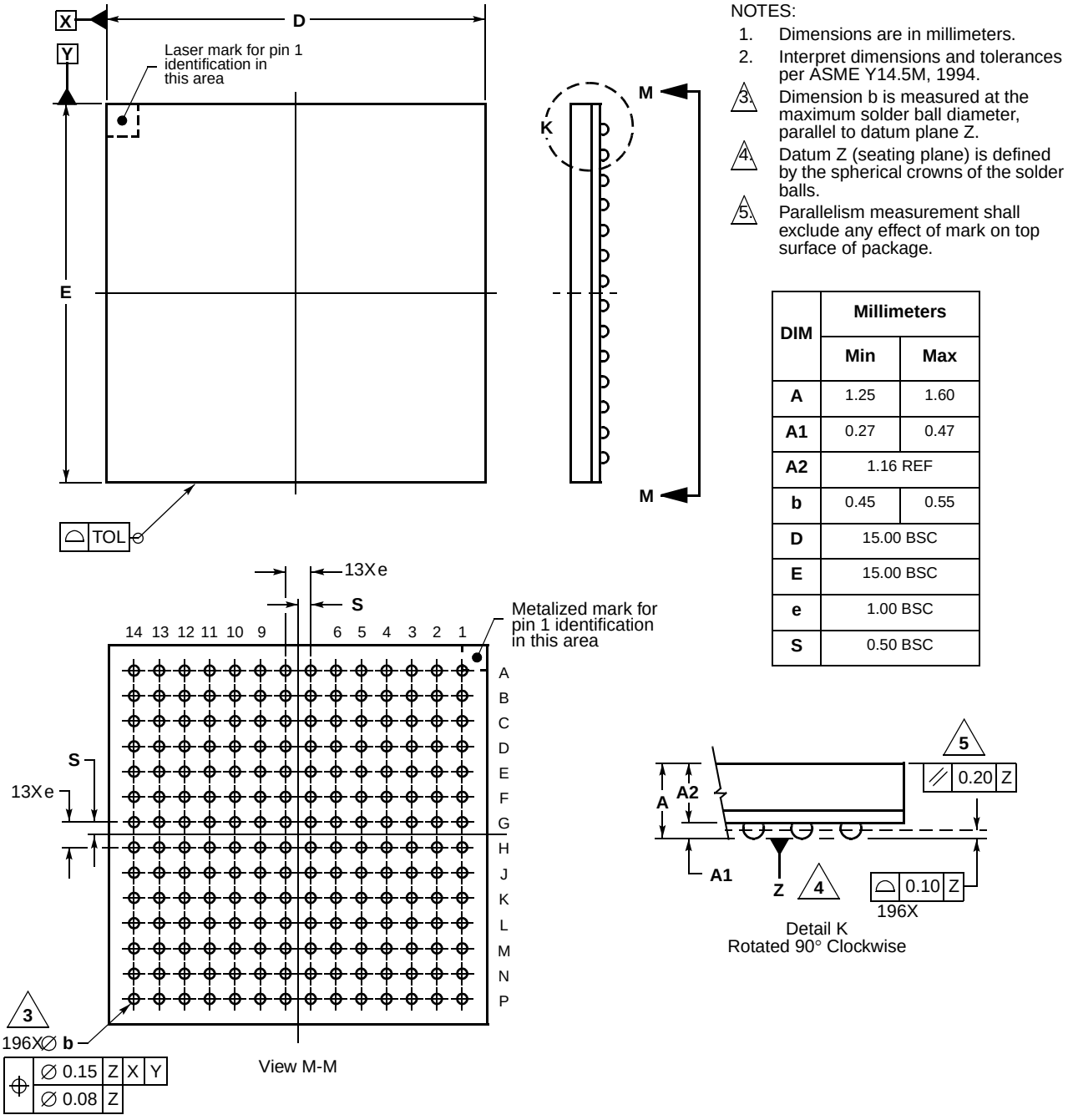
The FEC supports both an MII interface for 10/100 Mbps Ethernet and a seven-wire serial interface for 10 Mbps Ethernet. The interface mode is selected by R_CNTRL[MII_MODE]. In MII mode, the 802.3 standard defines and the FEC module supports 18 signals. These are shown in Table 4.

Table 4. MII Mode

Signal Description	MCF5271 Pin
Transmit clock	ETXCLK
Transmit enable	ETXEN
Transmit data	ETXD[3:0]
Transmit error	ETXER
Collision	ECOL
Carrier sense	ECRS
Receive clock	ERXCLK
Receive enable	ERXDV
Receive data	ERXD[3:0]

6.2 Package Dimensions—196 MAPBGA

Figure 4 shows MCF5270/71CVMxxx package dimensions.



NOTES:
1. Dimensions are in millimeters.
2. Interpret dimensions and tolerances per ASME Y14.5M, 1994.
3. Dimension b is measured at the maximum solder ball diameter, parallel to datum plane Z.
4. Datum Z (seating plane) is defined by the spherical crowns of the solder balls.
5. Parallelism measurement shall exclude any effect of mark on top surface of package.

DIM	Millimeters	
	Min	Max
A	1.25	1.60
A1	0.27	0.47
A2	1.16 REF	
b	0.45	0.55
D	15.00 BSC	
E	15.00 BSC	
e	1.00 BSC	
S	0.50 BSC	

Figure 4. 196 MAPBGA Package Dimensions (Case No. 1128A-01)

6.3 Pinout—160 QFP

Figure 5 shows a pinout of the MCF5271CABxxx package.

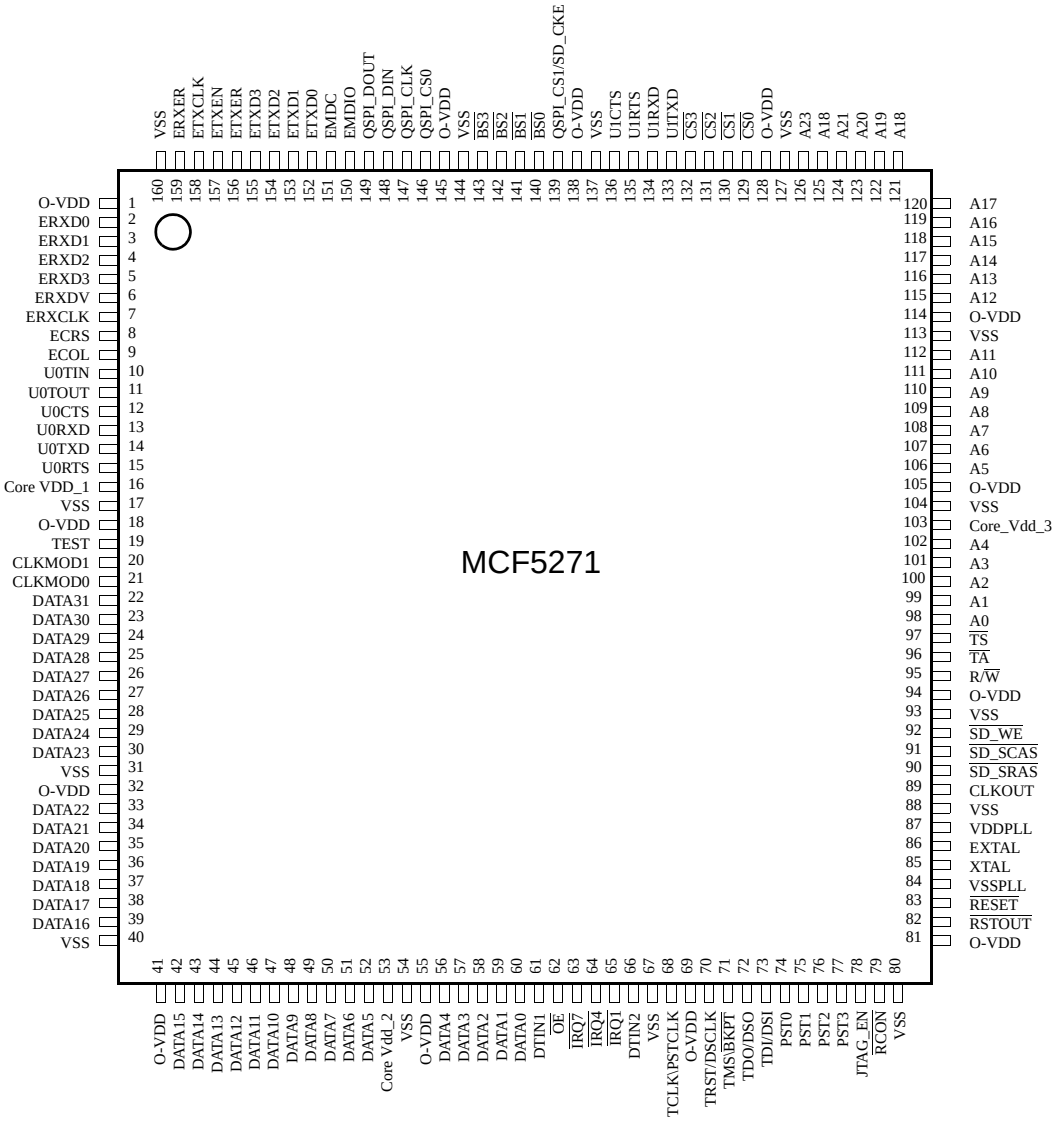


Figure 5. MCF5270/71CABxxx Pinout (160 QFP)

T_A= Ambient Temperature, °C

Θ_{JMA}= Package Thermal Resistance, Junction-to-Ambient, °C/W

$P_D = P_{INT} + P_{I/O}$

$P_{INT} = I_{DD} \times V_{DD}$, Watts - Chip Internal Power

$P_{I/O}$= Power Dissipation on Input and Output Pins — User Determined

For most applications $P_{I/O} < P_{INT}$ and can be ignored. An approximate relationship between P_D and T_J (if $P_{I/O}$ is neglected) is:

$$P_D = K \div (T_J + 273°C) \quad (2)$$

Solving equations 1 and 2 for K gives:

$$K = P_D \times (T_A + 273\ °C) + \Theta_{JMA} \times P_D^2 \quad (3)$$

where K is a constant pertaining to the particular part. K can be determined from equation (3) by measuring P_D (at equilibrium) for a known T_A. Using this value of K, the values of P_D and T_J can be obtained by solving equations (1) and (2) iteratively for any value of T_A.

7.3 DC Electrical Specifications

Table 9. DC Electrical Specifications[1]

Characteristic	Symbol	Min	Typical	Max	Unit
Core Supply Voltage	V_{DD}	1.4	—	1.6	V
Pad Supply Voltage	OV_{DD}	3.0	—	3.6	V
PLL Supply Voltage	V_{DDPLL}	3.0	—	3.6	V
Input High Voltage	V_{IH}	$0.7 \times OV_{DD}$	—	3.65	V
Input Low Voltage	V_{IL}	$V_{SS} - 0.3$	—	$0.35 \times OV_{DD}$	V
Input Hysteresis	V_{HYS}	$0.06 \times OV_{DD}$	—	—	mV
Input Leakage Current $V_{in} = V_{DD}$ or V_{SS}, Input-only pins	I_{in}	–1.0	—	1.0	µA
High Impedance (Off-State) Leakage Current $V_{in} = V_{DD}$ or V_{SS}, All input/output and output pins	I_{OZ}	–1.0	—	1.0	µA
Output High Voltage (All input/output and all output pins) I_{OH} = –5.0 mA	V_{OH}	OV_{DD} - 0.5	—	—	V
Output Low Voltage (All input/output and all output pins) I_{OL} = 5.0mA	V_{OL}	—	—	0.5	V
Weak Internal Pull Up Device Current, tested at V_{IL} Max.[2]	I_{APU}	–10	—	– 130	µA
Input Capacitance [3] All input-only pins All input/output (three-state) pins	C_{in}	 — —	—	 7 7	pF

Table 9. DC Electrical Specifications[1] (continued)

Characteristic	Symbol	Min	Typical	Max	Unit
Load Capacitance[4] Low drive strength High drive strength	C_L		— —	25 50	pF pF
Core Operating Supply Current [5] Master Mode	I_{DD}	—	135	150	mA
Pad Operating Supply Current Master Mode Low Power Modes	OI_{DD}	— —	100 TBD	— —	mA µA
DC Injection Current [3, 6, 7, 8] $V_{NEGCLAMP}$ =V_{SS}– 0.3 V, $V_{POSCLAMP}$ = V_{DD} + 0.3 Single Pin Limit Total processor Limit, Includes sum of all stressed pins	I_{IC}	 –1.0 –10		 1.0 10	 mA mA

1 Refer to Table 10 for additional PLL specifications.
2 Refer to the MCF5271 signals section for pins having weak internal pull-up devices.
3 This parameter is characterized before qualification rather than 100% tested.
4 pF load ratings are based on DC loading and are provided as an indication of driver strength. High speed interfaces require transmission line analysis to determine proper drive strength and termination. See High Speed Signal Propagation: Advanced Black Magic by Howard W. Johnson for design guidelines.
5 Current measured at maximum system clock frequency, all modules active, and default drive strength with matching load.
6 All functional non-supply pins are internally clamped to V_{SS} and their respective V_{DD}.
7 Input must be current limited to the value specified. To determine the value of the required current-limiting resistor, calculate resistance values for positive and negative clamp voltages, then use the larger of the two values.
8 Power supply must maintain regulation within operating V_{DD} range during instantaneous and operating maximum current conditions. If positive injection current ($V_{in} > V_{DD}$) is greater than I_{DD}, the injection current may flow out of V_{DD} and could result in external power supply going out of regulation. Insure external V_{DD} load will shunt current greater than maximum injection current. This will be the greatest risk when the processor is not consuming power. Examples are: if no system clock is present, or if clock rate is very low which would reduce overall power consumption. Also, at power-up, system clock is not present during the power-up sequence until the PLL has attained lock.

7.4 Oscillator and PLLMRFM Electrical Characteristics

Table 10. HiP7 PLLMRFM Electrical Specifications[1]

Num	Characteristic	Symbol	Min. Value	Max. Value	Unit
1	PLL Reference Frequency Range Crystal reference External reference 1:1 mode (NOTE: $f_{sys/2} = 2 \times f_{ref\_1:1}$)	 $f_{ref\_crystal}$ f_{ref_ext} $f_{ref\_1:1}$	 8 8 24	 25 25 75	MHz
2	Core frequency CLKOUT Frequency [2] External reference On-Chip PLL Frequency	f_{sys} $f_{sys/2}$	 0 $f_{ref} \div 32$	150 75 75	MHz MHz MHz
3	Loss of Reference Frequency [3, 5]	f_{LOR}	100	1000	kHz
4	Self Clocked Mode Frequency [4, 5]	f_{SCM}	10.25	15.25	MHz
5	Crystal Start-up Time [5, 6]	t_{cst}	—	10	ms

7.5 External Interface Timing Characteristics

Table 11 lists processor bus input timings.

NOTE

All processor bus timings are synchronous; that is, input setup/hold and output delay with respect to the rising edge of a reference clock. The reference clock is the CLKOUT output.

All other timing relationships can be derived from these values.

Table 11. Processor Bus Input Timing Specifications

Name	Characteristic[1]	Symbol	Min	Max	Unit
freq	System bus frequency	$f_{sys/2}$	50	75	MHz
B0	CLKOUT period	t_{cyc}	—	1/75	ns
Control Inputs					
B1a	Control input valid to CLKOUT high[2]	t_{CVCH}	9	—	ns
B1b	$\overline{\text{BKPT}}$ valid to CLKOUT high[3]	t_{BKVCH}	9	—	ns
B2a	CLKOUT high to control inputs invalid[2]	t_{CHCII}	0	—	ns
B2b	CLKOUT high to asynchronous control input $\overline{\text{BKPT}}$ invalid[3]	t_{BKNCH}	0	—	ns
Data Inputs					
B4	Data input (D[31:0]) valid to CLKOUT high	t_{DIVCH}	4	—	ns
B5	CLKOUT high to data input (D[31:0]) invalid	t_{CHDII}	0	—	ns

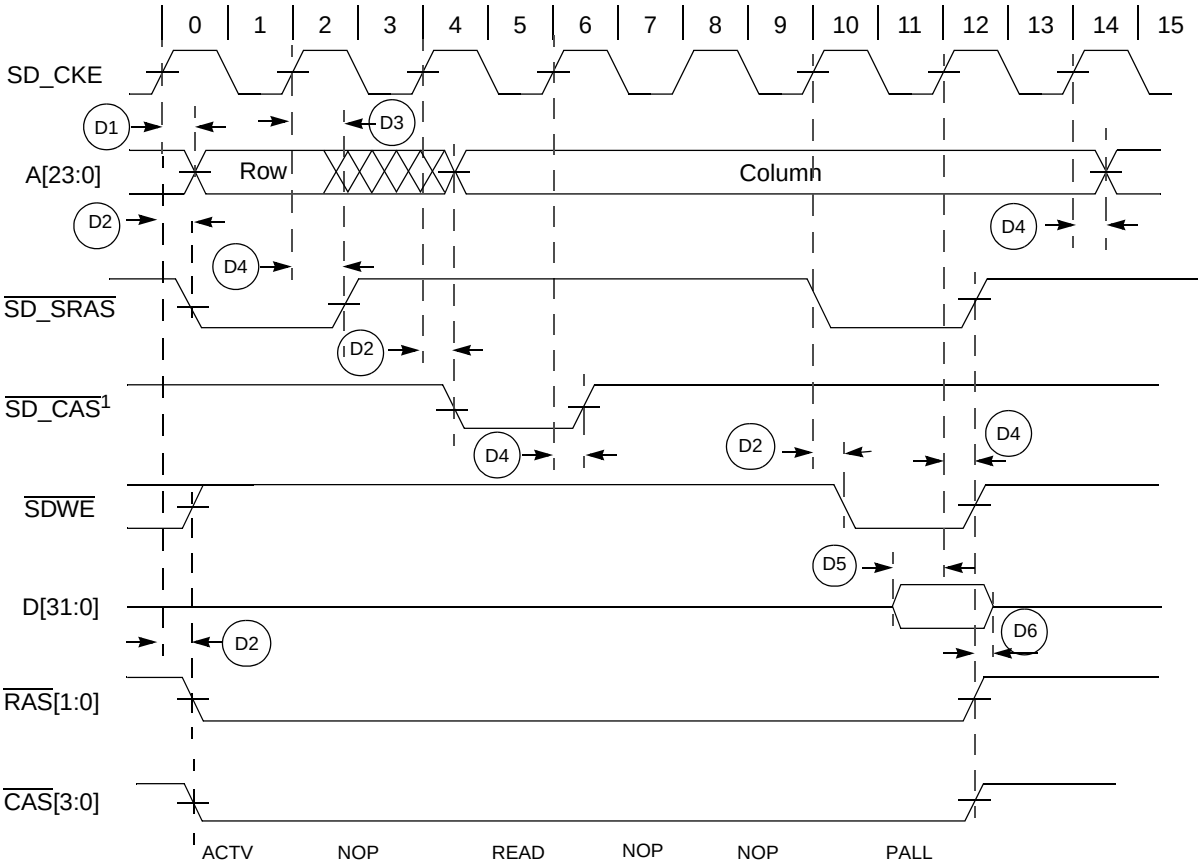
1 Timing specifications are tested using full drive strength pad configurations in a 50ohm transmission line environment..
2 $\overline{\text{TEA}}$ and $\overline{\text{TA}}$ pins are being referred to as control inputs.
3 Refer to figure A-19.

Table 12. External Bus Output Timing Specifications (continued)

Name	Characteristic	Symbol	Min	Max	Unit
Address and Attribute Outputs					
B8	CLKOUT high to address (A[23:0]) and control ($\overline{TS}$, $\overline{TSIZ}$[1:0], $\overline{TIP}$, R/$\overline{W}$) valid	t_{CHAV}	—	9	ns
B9	CLKOUT high to address (A[23:0]) and control ($\overline{TS}$, $\overline{TSIZ}$[1:0], $\overline{TIP}$, R/$\overline{W}$) invalid	t_{CHAI}	1.5	—	ns
Data Outputs					
B11	CLKOUT high to data output (D[31:0]) valid	t_{CHDOV}	—	9	ns
B12	CLKOUT high to data output (D[31:0]) invalid	t_{CHDOI}	1.5	—	ns
B13	CLKOUT high to data output (D[31:0]) high impedance	t_{CHDOZ}	—	9	ns

1 $\overline{CS}$ transitions after the falling edge of CLKOUT.
2 $\overline{BS}$ transitions after the falling edge of CLKOUT.
3 $\overline{OE}$ transitions after the falling edge of CLKOUT.

Figure 11 shows an SDRAM read cycle.



1 DACR[CASL] = 2

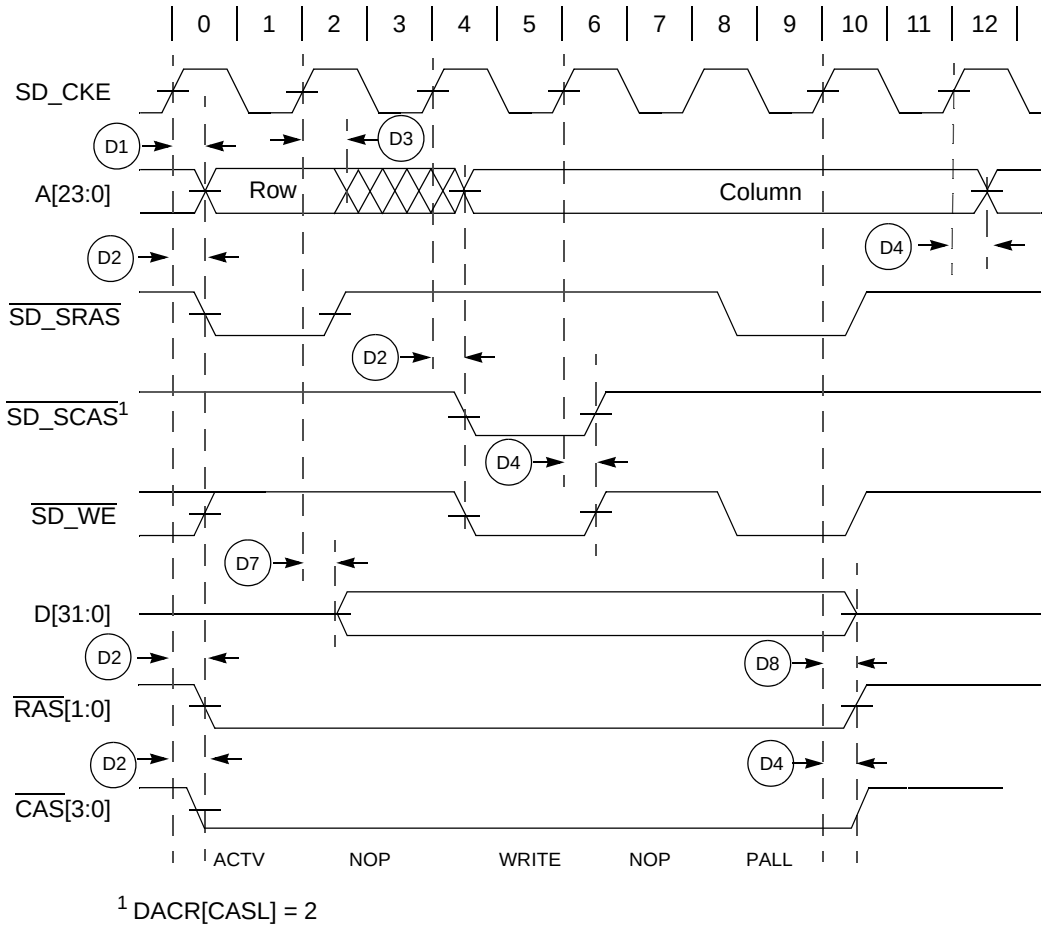
Figure 11. SDRAM Read Cycle

Table 13. SDRAM Timing

NUM	Characteristic	Symbol	Min	Max	Unit
D1	CLKOUT high to SDRAM address valid	t_{CHDAV}	—	9	ns
D2	CLKOUT high to SDRAM control valid	t_{CHDCV}	—	9	ns
D3	CLKOUT high to SDRAM address invalid	t_{CHDAI}	1.5	—	ns
D4	CLKOUT high to SDRAM control invalid	t_{CHDCI}	1.5	—	ns
D5	SDRAM data valid to CLKOUT high	t_{DDVCH}	4	—	ns
D6	CLKOUT high to SDRAM data invalid	t_{CHDDI}	1.5	—	ns
D7[1]	CLKOUT high to SDRAM data valid	t_{CHDDVW}	—	9	ns
D8[1]	CLKOUT high to SDRAM data invalid	t_{CHDDIW}	1.5	—	ns

1 D7 and D8 are for write cycles only.

Figure 12 shows an SDRAM write cycle.



1 DACR[CASL] = 2

Figure 12. SDRAM Write Cycle

7.7 General Purpose I/O Timing

Table 14. GPIO Timing[1]

NUM	Characteristic	Symbol	Min	Max	Unit
G1	CLKOUT High to GPIO Output Valid	t_{CHPOV}	—	10	ns
G2	CLKOUT High to GPIO Output Invalid	t_{CHPOI}	1.5	—	ns
G3	GPIO Input Valid to CLKOUT High	t_{PVCH}	9	—	ns
G4	CLKOUT High to GPIO Input Invalid	t_{CHPI}	1.5	—	ns

1 GPIO pins include: INT, UART, Timer, $\overline{\text{DREQ}n}$ and $\overline{\text{DACK}n}$ pins.

7.9 I²C Input/Output Timing Specifications

Table 16 lists specifications for the I²C input timing parameters shown in Figure 15.

Table 16. I²C Input Timing Specifications between I2C_SCL and I2C_SDA

Num	Characteristic	Min	Max	Units
I1	Start condition hold time	2	—	t_{cyc}
I2	Clock low period	8	—	t_{cyc}
I3	I2C_SCL/I2C_SDA rise time (V_{IL} = 0.5 V to V_{IH} = 2.4 V)	—	1	ms
I4	Data hold time	0	—	ns
I5	I2C_SCL/I2C_SDA fall time (V_{IH} = 2.4 V to V_{IL} = 0.5 V)	—	1	ms
I6	Clock high time	4	—	t_{cyc}
I7	Data setup time	0	—	ns
I8	Start condition setup time (for repeated start condition only)	2	—	t_{cyc}
I9	Stop condition setup time	2	—	t_{cyc}

Table 17 lists specifications for the I²C output timing parameters shown in Figure 15.

Table 17. I²C Output Timing Specifications between I2C_SCL and I2C_SDA

Num	Characteristic	Min	Max	Units
I1[1]	Start condition hold time	6	—	t_{cyc}
I2 [1]	Clock low period	10	—	t_{cyc}
I3 [2]	I2C_SCL/I2C_SDA rise time (V_{IL} = 0.5 V to V_{IH} = 2.4 V)	—	—	µs
I4 [1]	Data hold time	7	—	t_{cyc}
I5 [3]	I2C_SCL/I2C_SDA fall time (V_{IH} = 2.4 V to V_{IL} = 0.5 V)	—	3	ns
I6 [1]	Clock high time	10	—	t_{cyc}
I7 [1]	Data setup time	2	—	t_{cyc}
I8 [1]	Start condition setup time (for repeated start condition only)	20	—	t_{cyc}
I9 [1]	Stop condition setup time	10	—	t_{cyc}

1 Note: Output numbers depend on the value programmed into the IFDR; an IFDR programmed with the maximum frequency (IFDR = 0x20) results in minimum output timings as shown in Table 17. The I²C interface is designed to scale the actual data transition time to move it to the middle of the I2C_SCL low period. The actual position is affected by the prescale and division values programmed into the IFDR; however, the numbers given in Table 17 are minimum values.

2 Because I2C_SCL and I2C_SDA are open-collector-type outputs, which the processor can only actively drive low, the time I2C_SCL or I2C_SDA take to reach a high level depends on external signal capacitance and pull-up resistor values.

3 Specified at a nominal 50-pF load.

Figure 15 shows timing for the values in Table 16 and Table 17.

7.10.2 MII Transmit Signal Timing (ETXD[3:0], ETXEN, ETXER, ETXCLK)

Table 19 lists MII transmit channel timings.

The transmitter functions correctly up to a ETXCLK maximum frequency of 25 MHz +1%. The processor clock frequency must exceed twice the ETXCLK frequency.

Table 19. MII Transmit Signal Timing

Num	Characteristic	Min	Max	Unit
M5	ETXCLK to ETXD[3:0], ETXEN, ETXER invalid	5	—	ns
M6	ETXCLK to ETXD[3:0], ETXEN, ETXER valid	—	25	ns
M7	ETXCLK pulse width high	35%	65%	ETXCLK period
M8	ETXCLK pulse width low	35%	65%	ETXCLK period

Figure 17 shows MII transmit signal timings listed in Table 19.

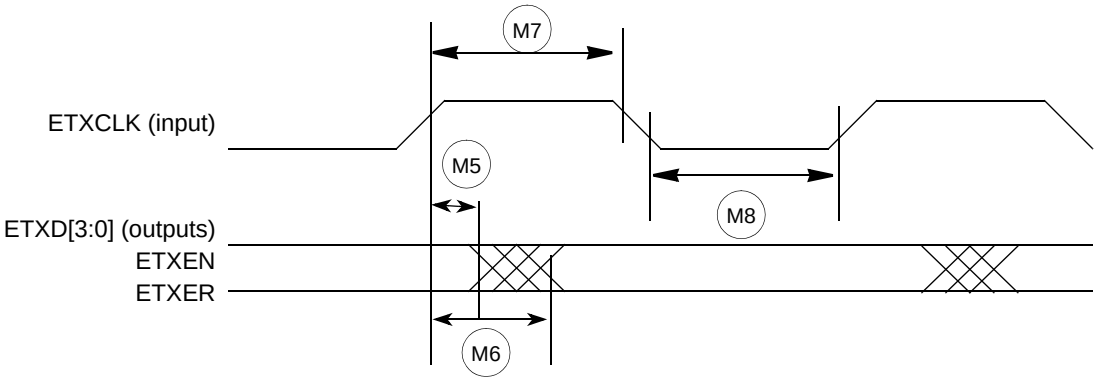


Figure 17. MII Transmit Signal Timing Diagram

7.10.3 MII Async Inputs Signal Timing (ECRS and ECOL)

Table 20 lists MII asynchronous inputs signal timing.

Table 20. MII Async Inputs Signal Timing

Num	Characteristic	Min	Max	Unit
M9	ECRS, ECOL minimum pulse width	1.5	—	ETXCLK period

Figure 18 shows MII asynchronous input timings listed in Table 20.

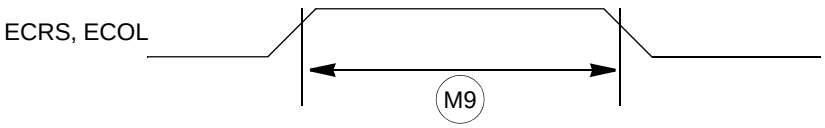


Figure 18. MII Async Inputs Timing Diagram

7.10.4 MII Serial Management Channel Timing (EMDIO and EMDC)

Table 21 lists MII serial management channel timings. The FEC functions correctly with a maximum MDC frequency of 2.5 MHz.

Table 21. MII Serial Management Channel Timing

Num	Characteristic	Min	Max	Unit
M10	EMDC falling edge to EMDIO output invalid (minimum propagation delay)	0	—	ns
M11	EMDC falling edge to EMDIO output valid (max prop delay)	—	25	ns
M12	EMDIO (input) to EMDC rising edge setup	10	—	ns
M13	EMDIO (input) to EMDC rising edge hold	0	—	ns
M14	EMDC pulse width high	40%	60%	MDC period
M15	EMDC pulse width low	40%	60%	MDC period

Figure 19 shows MII serial management channel timings listed in Table 21.

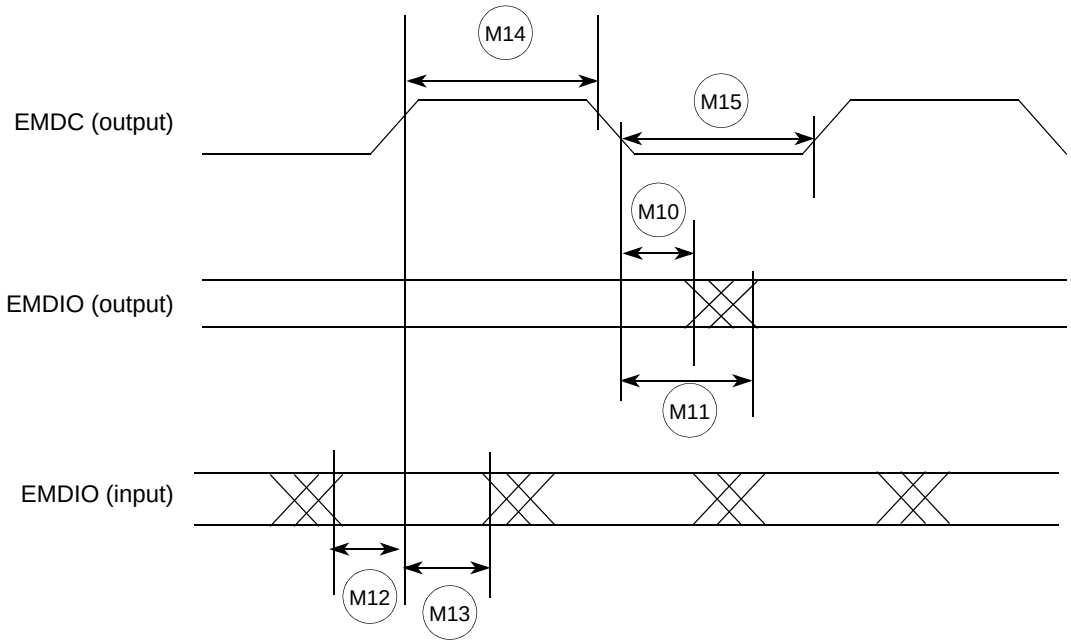


Figure 19. MII Serial Management Channel Timing Diagram

7.13 JTAG and Boundary Scan Timing

Table 24. JTAG and Boundary Scan Timing

Num	Characteristics[1]	Symbol	Min	Max	Unit
J1	TCLK Frequency of Operation	f_{JCYC}	DC	1/4	$f_{sys/2}$
J2	TCLK Cycle Period	t_{JCYC}	4	—	t_{CYC}
J3	TCLK Clock Pulse Width	t_{JCW}	26	—	ns
J4	TCLK Rise and Fall Times	t_{JCRF}	0	3	ns
J5	Boundary Scan Input Data Setup Time to TCLK Rise	t_{BSDST}	4	—	ns
J6	Boundary Scan Input Data Hold Time after TCLK Rise	t_{BSDHT}	26	—	ns
J7	TCLK Low to Boundary Scan Output Data Valid	t_{BSDV}	0	33	ns
J8	TCLK Low to Boundary Scan Output High Z	t_{BSDZ}	0	33	ns
J9	TMS, TDI Input Data Setup Time to TCLK Rise	t_{TAPBST}	4	—	ns
J10	TMS, TDI Input Data Hold Time after TCLK Rise	t_{TAPBHT}	10	—	ns
J11	TCLK Low to TDO Data Valid	t_{TDODV}	0	26	ns
J12	TCLK Low to TDO High Z	t_{TDODZ}	0	8	ns
J13	$\overline{TRST}$ Assert Time	t_{TRSTAT}	100	—	ns
J14	$\overline{TRST}$ Setup Time (Negation) to TCLK High	t_{TRSTST}	10	—	ns

1 JTAG_EN is expected to be a static signal. Hence, specific timing is not associated with it.

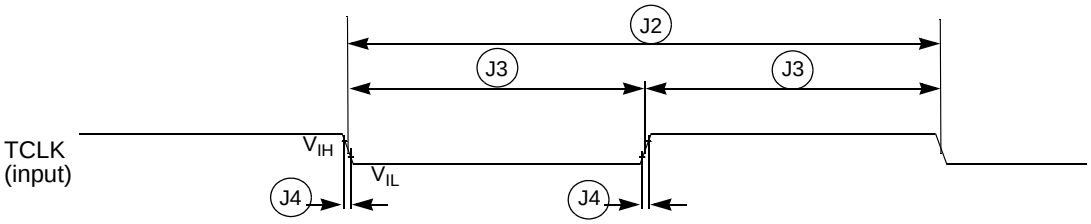


Figure 21. Test Clock Input Timing

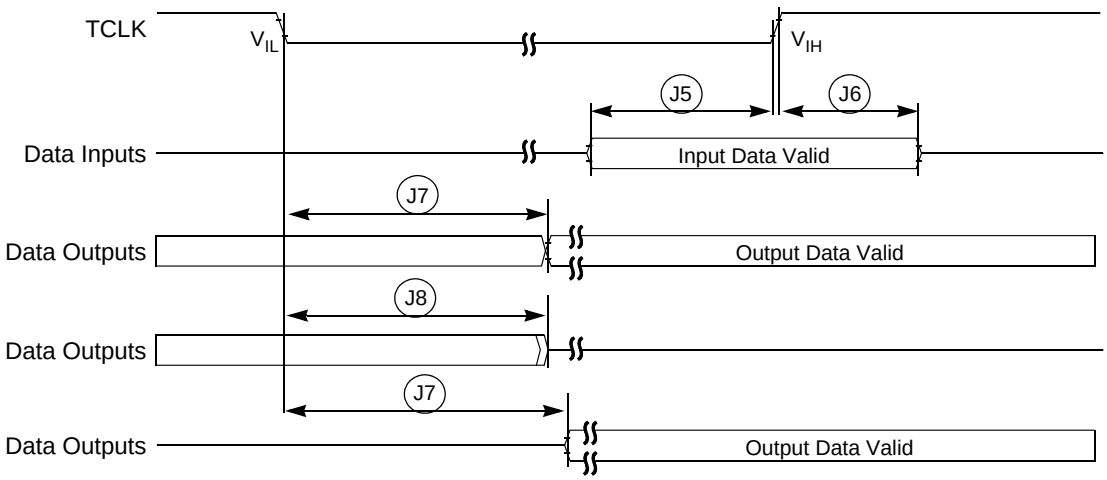


Figure 22. Boundary Scan (JTAG) Timing

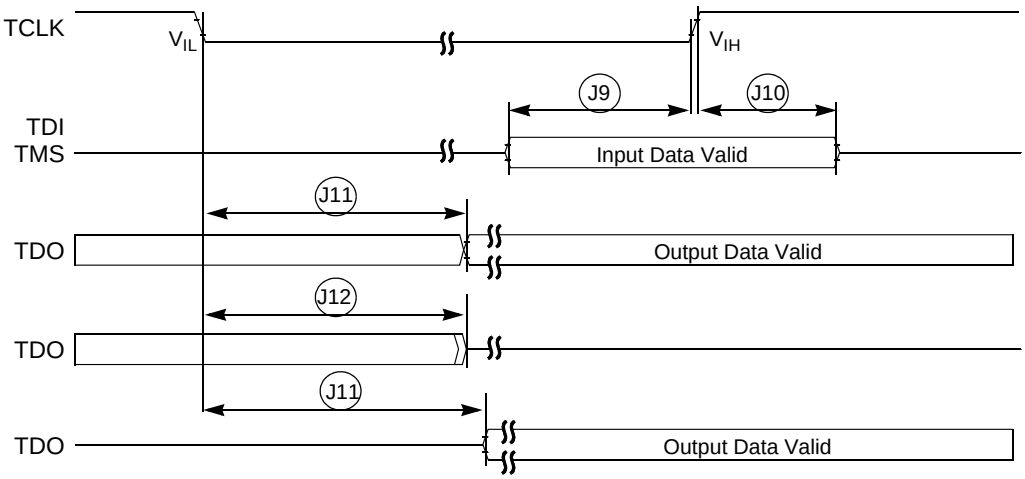


Figure 23. Test Access Port Timing

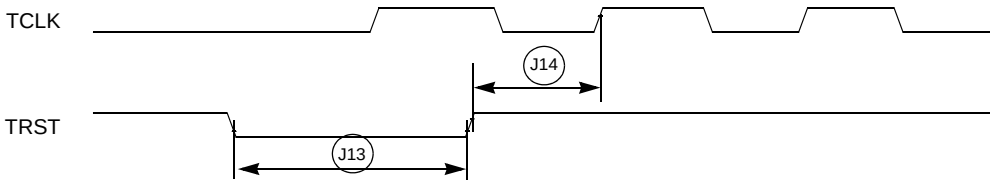


Figure 24. $\overline{\text{TRST}}$ Timing

7.14 Debug AC Timing Specifications

Table 25 lists specifications for the debug AC timing parameters shown in Figure 26.

Table 25. Debug AC Timing Specification

Num	Characteristic	150 MHz		Units
		Min	Max	
DE0	PSTCLK cycle time	—	0.5	t_{cyc}
DE1	PST valid to PSTCLK high	4	—	ns
DE2	PSTCLK high to PST invalid	1.5	—	ns
DE3	DSCLK cycle time	5	—	t_{cyc}
DE4	DSI valid to DSCLK high	1	—	t_{cyc}
DE5[1]	DSCLK high to DSO invalid	4	—	t_{cyc}
DE6	$\overline{\text{BKPT}}$ input data setup time to CLKOUT rise	4	—	ns
DE7	CLKOUT high to $\overline{\text{BKPT}}$ high Z	0	10	ns

1 DSCLK and DSI are synchronized internally. D4 is measured from the synchronized DSCLK input relative to the rising edge of CLKOUT.

Figure 25 shows real-time trace timing for the values in Table 25.

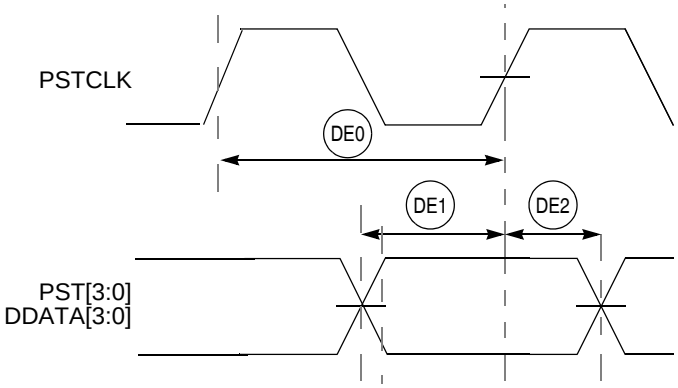


Figure 25. Real-Time Trace AC Timing

Figure 26 shows BDM serial port AC timing for the values in Table 25.

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